

**INFORMATION
DISCLOSURE
STATEMENT**

Atty. Docket No.: 110.0142 0101

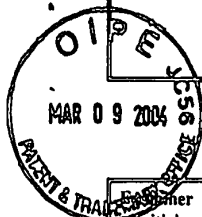
Serial No.: 09/691,006

Applicant(s): ZHAN et al.

Confirmation No.: 4510

Application Filing Date: 18 October 2000

Group: 2877

Information Disclosure Statement mailed: *March 9, 2004*
U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>KP</i>	4,893,932	01/16/90	Knollenberg	<i>—</i>	<i>—</i>	
<i>KP</i>	5,220,403	06/15/93	Batchelder et al.	<i>—</i>	<i>—</i>	
<i>KP</i>	5,822,073	10/13/98	Yee et al.	<i>—</i>	<i>—</i>	
<i>KP</i>	5,991,488	11/23/99	Salamon et al.	<i>—</i>	<i>—</i>	
<i>KP</i>	6,127,183	10/03/00	Ivarsson et al.	<i>—</i>	<i>—</i>	
<i>KP</i>	6,493,097	12/10/02	Ivarsson	<i>—</i>	<i>—</i>	
<i>KP</i>	6,594,011	07/15/03	Kempen	<i>—</i>	<i>—</i>	

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation
						Yes No
		<i>None</i>				

OTHER DOCUMENTS (Including Authors, Title, Date, Pertinent Papers, etc.)

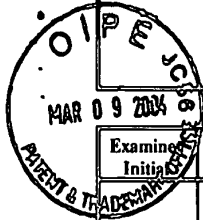
Examiner Initial	Document Description
<i>KP</i>	Azzam, "Differential reflection phase shift under conditions of attenuated internal reflection," <i>J. Opt. Soc. Am. A</i> , 1999;16(7):1700-1702.
<i>KP</i>	Bu-Abbud et al., "Characterization of Fabrication Damage in SrTiO ₃ by Internal and External Measurements," <i>Surface Science</i> , 1980;96:329-345.
<i>KP</i>	Burshta et al., "Ellipsometry of guided wave polaritons at solid surfaces," <i>Surface Science</i> , 1994;301:399-404.
<i>KP</i>	Ikeda et al., "Molecular orientation near the surface of a smectic liquid crystal cell showing V-shaped switching by means of attenuated total internal reflection ellipsometry," <i>Physical Review E</i> , 2001;63:061703-1-7.
<i>KP</i>	Irene, "Ultra-thin SiO ₂ film studies: index, thickness, roughness and the initial oxidation regime," <i>Solid State Electronics</i> , 2001;45:1207-1217.

EXAMINER

Date Considered

*Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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	Applicant(s): ZHAN et al.	Confirmation No.: 4510
	Application Filing Date: 18 October 2000	Group: 2877
	Information Disclosure Statement mailed: <i>March 9, 2004</i>	



Examiner Initials	Document Description
<i>HP</i>	Johansen et al., "Imaging surface plasmon resonance sensor based on multiple wavelengths: Sensitivity considerations," <i>Review of Scientific Instruments</i> , 2000;71(9):3530-3538.
<i>HP</i>	Moy, "Immersion ellipsometry," <i>Applied Optics</i> , 1981;20(22):3821-3822.
<i>HP</i>	Pokrowsky, "Optical methods for thickness measurements on thin metal films," <i>Applied Optics</i> , 1991;30(22):3228-3232.
<i>HP</i>	Takabayashi et al., "Propagation length of guided waves in lossy Si film sandwiched by identical dielectrics," <i>J. Opt. Soc. Am. B</i> , 1995;12(12):2406-2411.
<i>HP</i>	Tiwald et al., "Determination of the mid-IR optical constants of water and lubricants using IR ellipsometry combined with an ATR cell," <i>Thin Solid Films</i> , 1998;313-314:718-721.
<i>HP</i>	Yablonskii et al., "Control of the bias tilt angles in nematic liquid crystals," <i>J. Appl. Phys.</i> , 1999;85(5):2556-2561.

EXAMINER <i>Askan</i>	Date Considered <i>4/26/04</i>
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INFORMATION DISCLOSURE STATEMENT	Atty. Docket No.: 110.0142 0101	Serial No.: 09/691,006
	Applicant(s): ZHAN et al.	Confirmation No.: 4510
	Application Filing Date: 18 October 2000	Group: 2877
	Information Disclosure Statement mailed: <i>November 7, 2003</i>	

**U.S. PATENT DOCUMENTS**

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
			<i>None</i>			

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation
			<i>None</i>			Yes No

OTHER DOCUMENTS (Including Authors, Title, Date, Pertinent Papers, etc.)

Examiner Initial	Document Description
<i>HP</i>	Zhan et al., "High-Resolution Imaging Ellipsometer", <i>Applied Optics</i> , 2002; 41(22):4443-4450.
<i>HP</i>	Zhan et al., "Near-Field Nano-Ellipsometer for Ultrathin Film Characterization", <i>Journal of Microscopy</i> , 2003; 210:214-219.
<i>HP</i>	Zhan, "Novel Polarization Measurement and Manipulation Techniques for Nanometer Scale Applications", Thesis, University of Minnesota, August 2002; title pages, Acknowledgement, Abstract, and Table of Contents only: 12 pgs.
<i>HP</i>	Zhan, "Radiation Forces on a Dielectric Sphere Produced by Highly Focused Cylindrical Vector Beams", <i>Journal of Optics A: Pure and Applied Optics</i> , 2003; 5:229-232.

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EXAMINER <i>HP</i>	Date Considered <i>4/26/04</i>
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